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# Madrid 2008



## 11<sup>th</sup> International Conference on Non-Contact Atomic Force Microscopy

16<sup>th</sup>-19<sup>th</sup> September 2008

### SCOPE

1. Novel Instrumentation and techniques in dynamic AFM.
2. Small amplitude and lateral force measurements
3. Atomic resolution imaging on surfaces and molecular systems.
4. Highest resolution imaging of clusters, biomolecules and biological systems.
5. Atomic- and molecular-scale manipulation.
6. Theoretical analysis of contrast mechanisms. Forces & tunnelling phenomena.
7. Simulation of images and virtual SFM systems.
8. Measuring tip-sample interaction potentials and mapping force fields.
9. Mechanisms for damping and energy dissipation.
10. Amplitude modulation versus Frequency modulation imaging.
11. Imaging and spectroscopy in liquid environments.
12. Measuring nanoscale charges, work function and magnetic properties
13. Characterisation and modification of force microscopy tips at the atomic scale.

Abstract Submission Deadline:

16<sup>th</sup> May 2008

Early Registration Deadline:

13<sup>th</sup> June 2008

Conference Chairs:

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Satellite Conferences:

1<sup>st</sup> Multi-Frequency AFM Conference.  
*Madrid, 14<sup>th</sup>-15<sup>th</sup> September 2008.*

Workshop on Kelvin Probe Force Microscopy.  
*Madrid, 15<sup>th</sup> September 2008.*